5-BIT ADJUSTABLE, HIGH B.W. PASSIVE DELAY LINE (SERIES 3D10000)

data delay devices, inc. ®

FEATURES

- Delay adjustable in 31 steps
- Delay step sizes of 0.5ns to 3ns available
- Fast rise time for high frequency applications
- I/O reversible
- F-type female connectors
- Meets or exceeds MIL-D-23859C

PACKAGE

FUNCTIONAL DESCRIPTION

The 3D10000 device is a single-input, single-output, passive delay line. The signal input (IN) is reproduced at the output (OUT), shifted by a time (T_D) which can be adjusted via five binary-weighted switches. The value of these switches, multiplied by the device dash number, determines the device delay (referenced to the delay with all the switches off). The characteristic impedance of the device is nominally 75-ohms.

PIN DESCRIPTIONS

IN   Signal Input (BNC)
OUT Signal Output (BNC)

SERIES SPECIFICATIONS

- **Total Delay Tolerance:** 3%
- **Minimum Delay (all switches off):** 12ns
- **Impedance:** 75Ω
- **Ripple in pass-band:** Approx. 0.2dB
- **Dielectric breakdown:** 100 VDC
- **Operating temp:** -65°C to +125°C
- **Temperature coeff:** <100 PPM/°C
- **Case dimensions:** 17" x 13" x 5-1/4" (43.2cm x 33.0cm x 13.3cm)

DASH NUMBER SPECIFICATIONS

Part Number	Delay Step (ns)	Delay Range (ns)	Imped-ance (Ω)	3dB B.W. (MHz)
3D10000-0.5	0.5	15.5	75	380
3D10000-1	1.0	31.0	75	380
3D10000-1.4	1.4	43.4	75	380
3D10000-2	2.0	62.0	75	380
3D10000-3	3.0	93.0	75	380

Notes: 3db BW measured at maximum delay

Larger dash numbers are available in larger form factors. Please contact factory for details.

# PASSIVE DELAY LINE TEST SPECIFICATIONS

TEST CONDITIONS

INPUT:

Ambient Temperature:	$25^{o}C \pm 3^{o}C$
Input Pulse:	High = +0.5V typical
	Low = -0.5V typical
Source Impedance:	50Ω Max.
Rise/Fall Time:	3.0 ns Max. (measured at 10% and 90% levels)
Pulse Width:	PW_{IN} = 100ns
Period:	PER_{IN} = 1000ns

OUTPUT:

R$_{load}$:	10MΩ
C$_{load}$:	10pf
Threshold:	50% (Rising & Falling)

NOTE: The above conditions are for test only and do not in any way restrict the operation of the device.
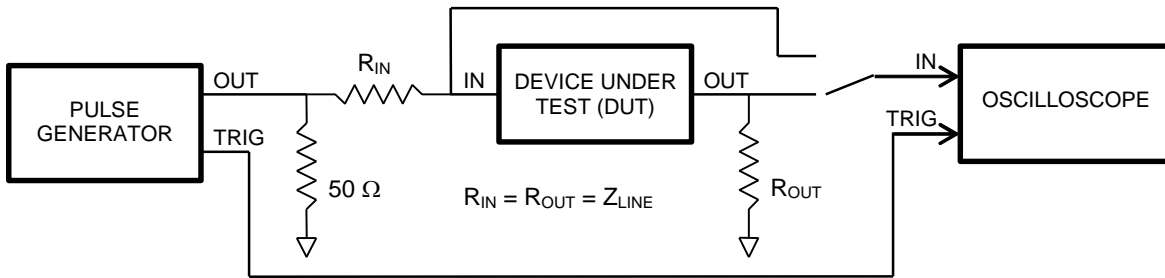
Test Setup (Delay Measurements)
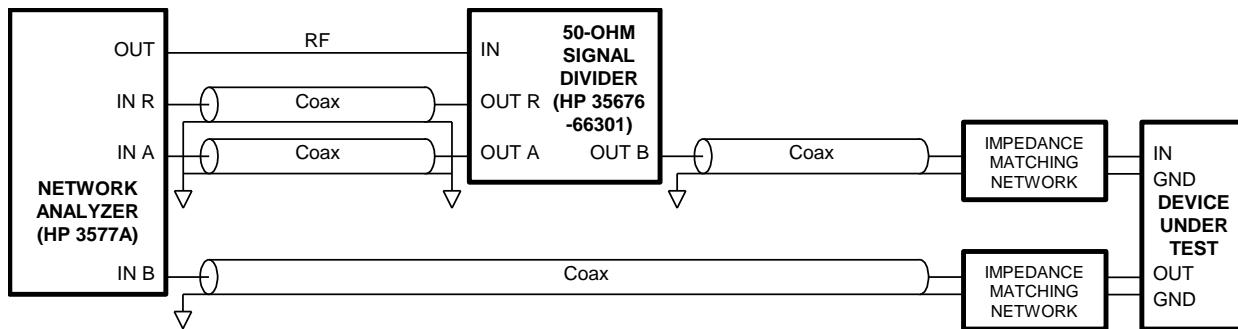
Test Setup (Frequency Response)